

Search Notes**Application/Control No.**

10/652,496

Examiner

Chau Nguyen

Applicant(s)/Patent under Reexamination

OHASHI ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	517	1/27/2006	CN
715	520	1/27/2006	CN
715	507	1/27/2006	CN
715	505	1/27/2006	CN
715	908	1/27/2006	CN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	01/26/2006	CN
	1/27/2006	CN
	1/30/2006	CN
NPL Search on IEEE Database	1/30/2006	CN
Updated Search on East Reports	7/13/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner